

Notice of References Cited	Application/Control No. 10/557,350	Applicant(s)/Patent Under Reexamination STEK ET AL.	
	Examiner LINH T. NGUYEN	Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0176335	11-2002	Miyanabe et al.	369/47.17
*	B	US-2005/0201230	09-2005	Kurobe, Shinichi	369/047.27
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
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NON-PATENT DOCUMENTS

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